

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. :  
Applicant : HINDERLING et al.  
Filed : Herewith  
TC/A.U. :  
Examiner :

Docket No. : 2235-158  
Customer No. : 06449  
Confirmation No. :

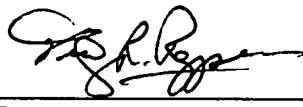
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**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application. The publications are listed on the attached form PTO-1449.

Respectfully submitted,

By   
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Complete if Known <b>10/583544</b>	
				Application Number	
				Filing Date	
				First Named Inventor	
				Group Art Unit	
				Examiner Name	
				Confirmation No.	
Sheet	1	of	1	Attorney Docket Number	2235-158

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>
		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
	1	DE	101 28 484	A1	Asahi Optical Co. Ltd	03-21-2002	AB
	2	EP	0 448 111	A2	Perceptron Inc.	09-25-1991	
	3	WO	01/29576 (abstract only)	A	PSC Scanning Inc.	04-26-2001	AB
	4	EP	0 768 542	A1	Topcon Corp.	04-16-1997	
	5	WO	03/002939	A1	Robert Bosch GmbH	01-09-2003	AB
	6	DE	198 40 049	A1	Leica Geosystems AG	04-06-2000	AB
	7	EP	0 635 729	A1	Nippon Denso Co.	01-25-1995	
	8	DE	43 16 348	A1	Leica Heerbrugg AG	11-17-1994	AB
Examiner Signature		/Luke Ratcliffe/			Date Considered	02/20/2008	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code. <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible.

<sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.